Welcome to E-XFL.COM

Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	2400
Number of Logic Elements/Cells	10800
Total RAM Bits	81920
Number of I/O	404
Number of Gates	468252
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	560-LBGA Exposed Pad, Metal
Supplier Device Package	560-MBGA (42.5x42.5)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcv400-6bg560c

Virtex Device/Package Combinations and Maximum I/O

Table 3: **Virtex Family Maximum User I/O by Device/Package (Excluding Dedicated Clock Pins)**

Package	XCV50	XCV100	XCV150	XCV200	XCV300	XCV400	XCV600	XCV800	XCV1000
CS144	94	94							
TQ144	98	98							
PQ240	166	166	166	166	166				
HQ240						166	166	166	
BG256	180	180	180	180					
BG352			260	260	260				
BG432					316	316	316	316	
BG560						404	404	404	404
FG256	176	176	176	176					
FG456			260	284	312				
FG676						404	444	444	
FG680							512	512	512

Virtex Ordering Information

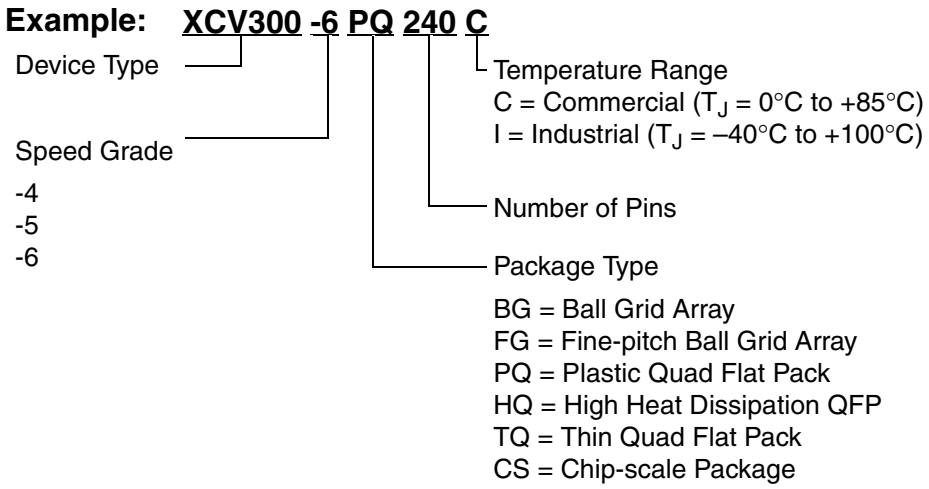


Figure 1: **Virtex Ordering Information**

more I/O pins convert to V_{REF} pins. Since these are always a superset of the V_{REF} pins used for smaller devices, it is possible to design a PCB that permits migration to a larger device if necessary. All the V_{REF} pins for the largest device anticipated must be connected to the V_{REF} voltage, and not used for I/O.

In smaller devices, some V_{CCO} pins used in larger devices do not connect within the package. These unconnected pins can be left unconnected externally, or can be connected to the V_{CCO} voltage to permit migration to a larger device if necessary.

In TQ144 and PQ/HQ240 packages, all V_{CCO} pins are bonded together internally, and consequently the same V_{CCO} voltage must be connected to all of them. In the CS144 package, bank pairs that share a side are interconnected internally, permitting four choices for V_{CCO}. In both cases, the V_{REF} pins remain internally connected as eight banks, and can be used as described previously.

Configurable Logic Block

The basic building block of the Virtex CLB is the logic cell (LC). An LC includes a 4-input function generator, carry logic, and a storage element. The output from the function generator in each LC drives both the CLB output and the D input of the flip-flop. Each Virtex CLB contains four LCs, organized in two similar slices, as shown in Figure 4.

Figure 5 shows a more detailed view of a single slice.

In addition to the four basic LCs, the Virtex CLB contains logic that combines function generators to provide functions of five or six inputs. Consequently, when estimating the number of system gates provided by a given device, each CLB counts as 4.5 LCs.

Look-Up Tables

Virtex function generators are implemented as 4-input look-up tables (LUTs). In addition to operating as a function generator, each LUT can provide a 16 x 1-bit synchronous RAM. Furthermore, the two LUTs within a slice can be combined to create a 16 x 2-bit or 32 x 1-bit synchronous RAM, or a 16x1-bit dual-port synchronous RAM.

The Virtex LUT can also provide a 16-bit shift register that is ideal for capturing high-speed or burst-mode data. This mode can also be used to store data in applications such as Digital Signal Processing.

Storage Elements

The storage elements in the Virtex slice can be configured either as edge-triggered D-type flip-flops or as level-sensitive latches. The D inputs can be driven either by the function generators within the slice or directly from slice inputs, bypassing the function generators.

In addition to Clock and Clock Enable signals, each Slice has synchronous set and reset signals (SR and BY). SR forces a storage element into the initialization state specified for it in the configuration. BY forces it into the opposite state. Alternatively, these signals can be configured to operate asynchronously. All of the control signals are independently invertible, and are shared by the two flip-flops within the slice.

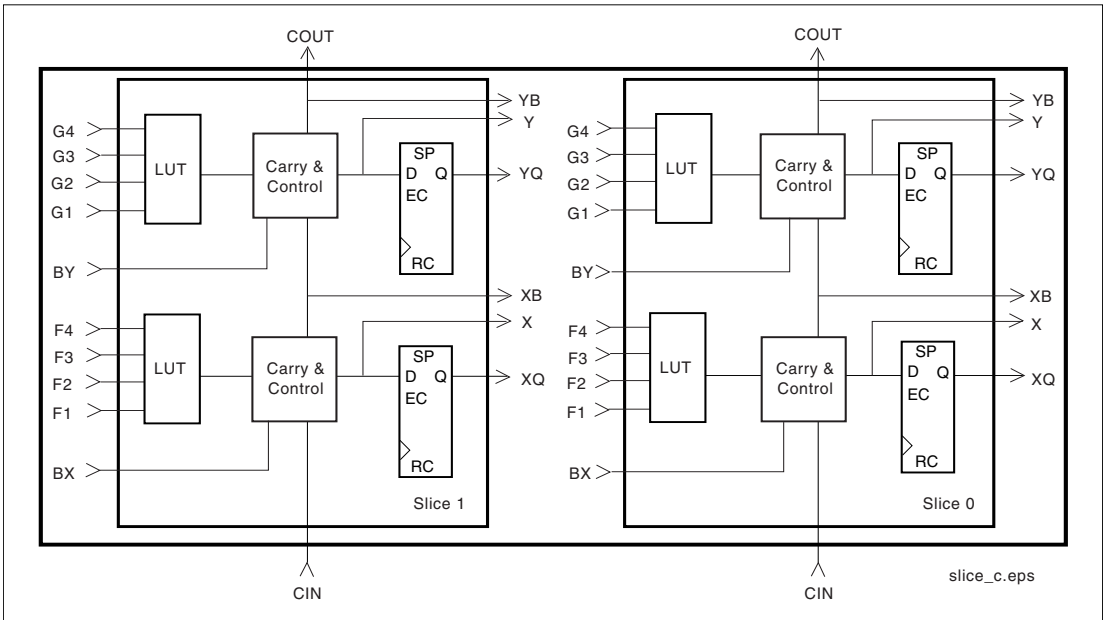


Figure 4: **2-Slice Virtex CLB**

Four dedicated clock pads are provided, one adjacent to each of the global buffers. The input to the global buffer is selected either from these pads or from signals in the general purpose routing.

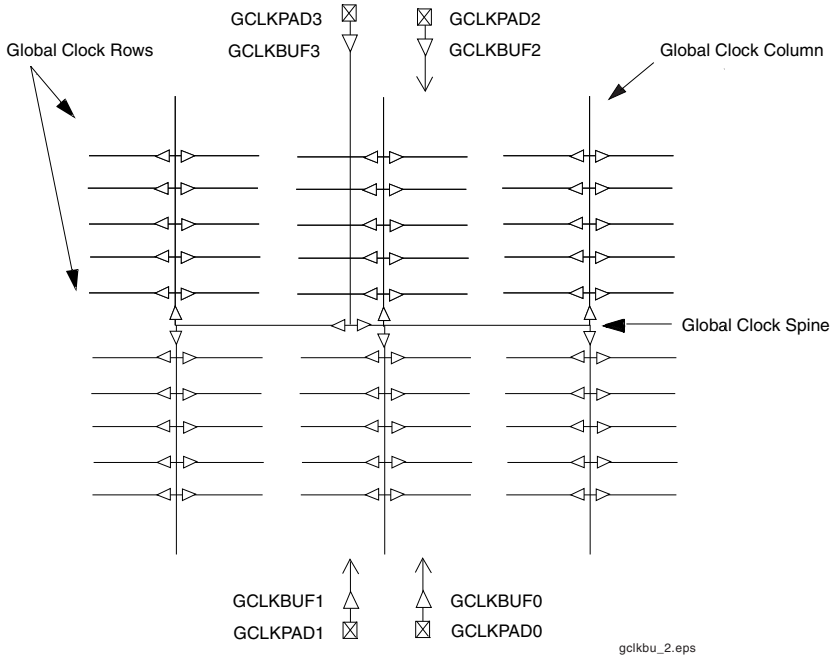


Figure 9: **Global Clock Distribution Network**

Delay-Locked Loop (DLL)

Associated with each global clock input buffer is a fully digital Delay-Locked Loop (DLL) that can eliminate skew between the clock input pad and internal clock-input pins throughout the device. Each DLL can drive two global clock networks.The DLL monitors the input clock and the distributed clock, and automatically adjusts a clock delay element. Clock edges reach internal flip-flops one to four clock periods after they arrive at the input. This closed-loop system effectively eliminates clock-distribution delay by ensuring that clock edges arrive at internal flip-flops in synchronism with clock edges arriving at the input.

In addition to eliminating clock-distribution delay, the DLL provides advanced control of multiple clock domains. The DLL provides four quadrature phases of the source clock, can double the clock, or divide the clock by 1.5, 2, 2.5, 3, 4, 5, 8, or 16.

The DLL also operates as a clock mirror. By driving the output from a DLL off-chip and then back on again, the DLL can be used to de-skew a board level clock among multiple Virtex devices.

In order to guarantee that the system clock is operating correctly prior to the FPGA starting up after configuration, the DLL can delay the completion of the configuration process until after it has achieved lock.

See **DLL Timing Parameters**, page 21 of Module 3, for frequency range information.

Boundary Scan

Virtex devices support all the mandatory boundary-scan instructions specified in the IEEE standard 1149.1. A Test Access Port (TAP) and registers are provided that implement the EXTEST, INTEST, SAMPLE/PRELOAD, BYPASS, IDCODE, USERCODE, and HIGHZ instructions. The TAP also supports two internal scan chains and configuration/readback of the device.The TAP uses dedicated package pins that always operate using LVTTL. For TDO to operate using LVTTL, the V_{CCO} for Bank 2 should be 3.3 V. Otherwise, TDO switches rail-to-rail between ground and V_{CCO}.

Boundary-scan operation is independent of individual IOB configurations, and unaffected by package type. All IOBs, including un-bonded ones, are treated as independent 3-state bidirectional pins in a single scan chain. Retention of the bidirectional test capability after configuration facilitates the testing of external interconnections, provided the user design or application is turned off.

Table 5 lists the boundary-scan instructions supported in Virtex FPGAs. Internal signals can be captured during EXTEST by connecting them to un-bonded or unused IOBs. They can also be connected to the unused outputs of IOBs defined as unidirectional input pins.

Before the device is configured, all instructions except USER1 and USER2 are available. After configuration, all instructions are available. During configuration, it is recommended that those operations using the boundary-scan register (SAMPLE/PRELOAD, INTEST, EXTEST) not be performed.

Master-Serial Mode

In master-serial mode, the CCLK output of the FPGA drives a Xilinx Serial PROM that feeds bit-serial data to the DIN input. The FPGA accepts this data on each rising CCLK edge. After the FPGA has been loaded, the data for the next device in a daisy-chain is presented on the DOUT pin after the rising CCLK edge.

The interface is identical to slave-serial except that an internal oscillator is used to generate the configuration clock (CCLK). A wide range of frequencies can be selected for CCLK which always starts at a slow default frequency. Configuration bits then switch CCLK to a higher frequency for the remainder of the configuration. Switching to a lower frequency is prohibited.

The CCLK frequency is set using the ConfigRate option in the bitstream generation software. The maximum CCLK frequency that can be selected is 60 MHz. When selecting a CCLK frequency, ensure that the serial PROM and any daisy-chained FPGAs are fast enough to support the clock rate.

On power-up, the CCLK frequency is 2.5 MHz. This frequency is used until the ConfigRate bits have been loaded when the frequency changes to the selected ConfigRate. Unless a different frequency is specified in the design, the default ConfigRate is 4 MHz.

Figure 12 shows a full master/slave system. In this system, the left-most device operates in master-serial mode. The remaining devices operate in slave-serial mode. The SPROM $\overline{\text{RESET}}$ pin is driven by $\overline{\text{INIT}}$, and the $\overline{\text{CE}}$ input is driven by DONE. There is the potential for contention on the DONE pin, depending on the start-up sequence options chosen.

Figure 14 shows the timing of master-serial configuration. Master-serial mode is selected by a <000> or <100> on the mode pins (M2, M1, M0). Table 8 shows the timing information for Figure 14.

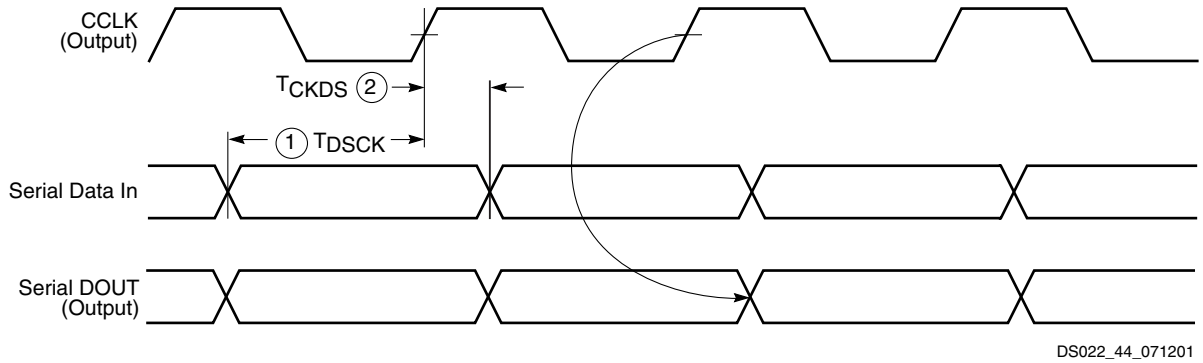


Figure 14: **Master-Serial Mode Programming Switching Characteristics**

At power-up, V_{CC} must rise from 1.0 V to V_{CC} min in less than 50 ms, otherwise delay configuration by pulling $\overline{\text{PROGRAM}}$ Low until V_{CC} is valid.

The sequence of operations necessary to configure a Virtex FPGA serially appears in Figure 15.

SelectMAP Mode

The SelectMAP mode is the fastest configuration option. Byte-wide data is written into the FPGA with a BUSY flag controlling the flow of data.

An external data source provides a byte stream, CCLK, a Chip Select ($\overline{\text{CS}}$) signal and a Write signal ($\overline{\text{WRITE}}$). If BUSY is asserted (High) by the FPGA, the data must be held until BUSY goes Low.

Data can also be read using the SelectMAP mode. If $\overline{\text{WRITE}}$ is not asserted, configuration data is read out of the FPGA as part of a readback operation.

In the SelectMAP mode, multiple Virtex devices can be chained in parallel. DATA pins (D7:D0), CCLK, $\overline{\text{WRITE}}$, $\overline{\text{BUSY}}$, $\overline{\text{PROGRAM}}$, DONE, and $\overline{\text{INIT}}$ can be connected in parallel between all the FPGAs. Note that the data is organized with the MSB of each byte on pin DO and the LSB of each byte on D7. The $\overline{\text{CS}}$ pins are kept separate, insuring that each FPGA can be selected individually. $\overline{\text{WRITE}}$ should be Low before loading the first bitstream and returned High after the last device has been programmed. Use $\overline{\text{CS}}$ to select the appropriate FPGA for loading the bitstream and sending the configuration data. at the end of the bitstream, deselect the loaded device and select the next target FPGA by setting its $\overline{\text{CS}}$ pin High. A free-running oscillator or other externally generated signal can be used for CCLK. The $\overline{\text{BUSY}}$ signal can be ignored for frequencies below 50 MHz. For details about frequencies above 50 MHz, see XAPP138, Virtex Configuration and Readback. Once all the devices have been programmed, the DONE pin goes High.

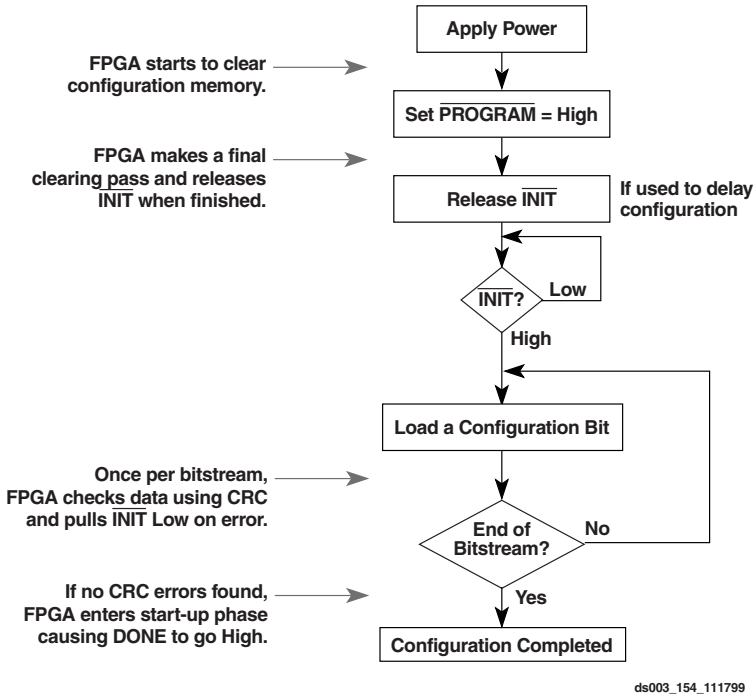


Figure 15: **Serial Configuration Flowchart**

After configuration, the pins of the SelectMAP port can be used as additional user I/O. Alternatively, the port can be retained to permit high-speed 8-bit readback.

Retention of the SelectMAP port is selectable on a design-by-design basis when the bitstream is generated. If retention is selected, PROHIBIT constraints are required to prevent the SelectMAP-port pins from being used as user I/O.

Multiple Virtex FPGAs can be configured using the Select-MAP mode, and be made to start-up simultaneously. To configure multiple devices in this way, wire the individual CCLK, Data, $\overline{\text{WRITE}}$, and BUSY pins of all the devices in parallel. The individual devices are loaded separately by asserting the $\overline{\text{CS}}$ pin of each device in turn and writing the appropriate data. see Table 9 for SelectMAP Write Timing Characteristics.

Table 9: **SelectMAP Write Timing Characteristics**

	Description		Symbol		Units
CCLK	D_{0-7} Setup/Hold	1/2	T_{SMDCC}/T_{SMCCD}	5.0 / 1.7	ns, min
	$\overline{\text{CS}}$ Setup/Hold	3/4	T_{SMCSCC}/T_{SMCCCS}	7.0 / 1.7	ns, min
	$\overline{\text{WRITE}}$ Setup/Hold	5/6	T_{SMCCW}/T_{SMWCC}	7.0 / 1.7	ns, min
	BUSY Propagation Delay	7	T_{SMCKBY}	12.0	ns, max
	Maximum Frequency		F_{CC}	66	MHz, max
	Maximum Frequency with no handshake		F_{CCNH}	50	MHz, max

Write

Write operations send packets of configuration data into the FPGA. The sequence of operations for a multi-cycle write operation is shown below. Note that a configuration packet can be split into many such sequences. The packet does not have to complete within one assertion of $\overline{\text{CS}}$, illustrated in Figure 16.

1. Assert $\overline{\text{WRITE}}$ and $\overline{\text{CS}}$ Low. Note that when $\overline{\text{CS}}$ is asserted on successive CCLKs, $\overline{\text{WRITE}}$ must remain either asserted or de-asserted. Otherwise an abort will be initiated, as described below.
2. Drive data onto D[7:0]. Note that to avoid contention, the data source should not be enabled while $\overline{\text{CS}}$ is Low and $\overline{\text{WRITE}}$ is High. Similarly, while $\overline{\text{WRITE}}$ is High, no more that one $\overline{\text{CS}}$ should be asserted.

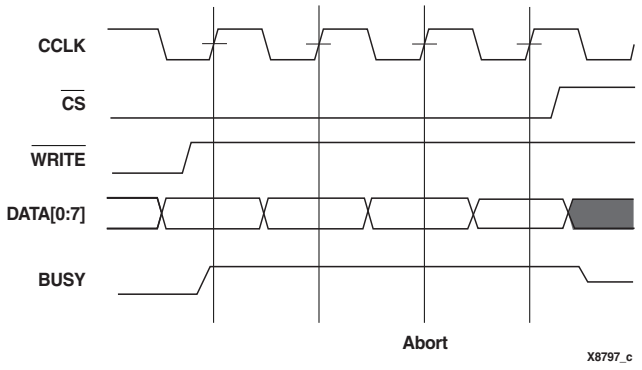


Figure 18: **SelectMAP Write Abort Waveforms**

Boundary-Scan Mode

In the boundary-scan mode, configuration is done through the IEEE 1149.1 Test Access Port. Note that the PROGRAM pin must be pulled High prior to reconfiguration. A Low on the PROGRAM pin resets the TAP controller and no JTAG operations can be performed.

Configuration through the TAP uses the CFG_IN instruction. This instruction allows data input on TDI to be converted into data packets for the internal configuration bus.

The following steps are required to configure the FPGA through the boundary-scan port (when using TCK as a start-up clock).

1. Load the CFG_IN instruction into the boundary-scan instruction register (IR)
2. Enter the Shift-DR (SDR) state
3. Shift a configuration bitstream into TDI
4. Return to Run-Test-Idle (RTI)
5. Load the JSTART instruction into IR
6. Enter the SDR state
7. Clock TCK through the startup sequence
8. Return to RTI

Configuration and readback via the TAP is always available. The boundary-scan mode is selected by a <101> or 001> on the mode pins (M2, M1, M0). For details on TAP characteristics, refer to XAPP139.

Configuration Sequence

The configuration of Virtex devices is a three-phase process. First, the configuration memory is cleared. Next, configuration data is loaded into the memory, and finally, the logic is activated by a start-up process.

Configuration is automatically initiated on power-up unless it is delayed by the user, as described below. The configuration process can also be initiated by asserting PROGRAM.

The end of the memory-clearing phase is signalled by INIT going High, and the completion of the entire process is signalled by DONE going High.

The power-up timing of configuration signals is shown in Figure 19. The corresponding timing characteristics are listed in Table 10.

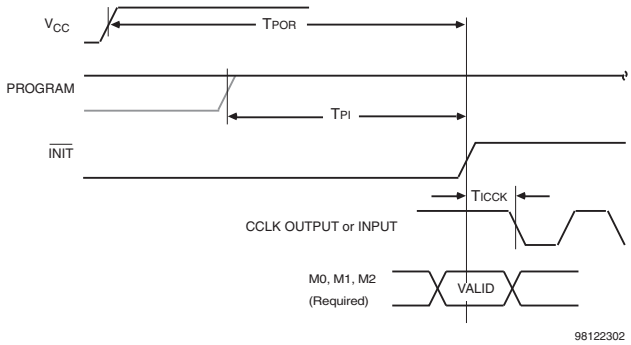


Figure 19: **Power-Up Timing Configuration Signals**

Table 10: **Power-up Timing Characteristics**

Description	Symbol	Value	Units
Power-on Reset	T_{POR}	2.0	ms, max
Program Latency	T_{PL}	100.0	µs, max
CCLK (output) Delay	T_{ICCK}	0.5	µs, min
		4.0	µs, max
Program Pulse Width	$T_{PROGRAM}$	300	ns, min

Delaying Configuration

INIT can be held Low using an open-drain driver. An open-drain is required since INIT is a bidirectional open-drain pin that is held Low by the FPGA while the configuration memory is being cleared. Extending the time that the pin is Low causes the configuration sequencer to wait. Thus, configuration is delayed by preventing entry into the phase where data is loaded.

Start-Up Sequence

The default Start-up sequence is that one CCLK cycle after DONE goes High, the global 3-state signal (GTS) is released. This permits device outputs to turn on as necessary.

One CCLK cycle later, the Global Set/Reset (GSR) and Global Write Enable (GWE) signals are released. This permits the internal storage elements to begin changing state in response to the logic and the user clock.

The relative timing of these events can be changed. In addition, the GTS, GSR, and GWE events can be made dependent on the DONE pins of multiple devices all going High, forcing the devices to start in synchronism. The sequence can also be paused at any stage until lock has been achieved on any or all DLLs.

Virtex™ 2.5 V Field Programmable Gate Arrays

DS003-3 (v4.0) March 1, 2013

Production Product Specification

Virtex Electrical Characteristics

Definition of Terms

Electrical and switching characteristics are specified on a per-speed-grade basis and can be designated as Advance, Preliminary, or Production. Each designation is defined as follows:

Advance: These speed files are based on simulations only and are typically available soon after device design specifications are frozen. Although speed grades with this designation are considered relatively stable and conservative, some under-reporting might still occur.

Preliminary: These speed files are based on complete ES (engineering sample) silicon characterization. Devices and speed grades with this designation are intended to give a better indication of the expected performance of production silicon. The probability of under-reporting delays is greatly reduced as compared to Advance data.

Production: These speed files are released once enough production silicon of a particular device family member has been characterized to provide full correlation between speed files and devices over numerous production lots. There is no under-reporting of delays, and customers receive formal notification of any subsequent changes. Typically, the slowest speed grades transition to Production before faster speed grades.

All specifications are representative of worst-case supply voltage and junction temperature conditions. The parameters included are common to popular designs and typical applications. Contact the factory for design considerations requiring more detailed information.

Table 1 correlates the current status of each Virtex device with a corresponding speed file designation.

Table 1: **Virtex Device Speed Grade Designations**

Device	Speed Grade Designations		
	Advance	Preliminary	Production
XCV50			–6, –5, –4
XCV100			–6, –5, –4
XCV150			–6, –5, –4
XCV200			–6, –5, –4
XCV300			–6, –5, –4
XCV400			–6, –5, –4
XCV600			–6, –5, –4
XCV800			–6, –5, –4
XCV1000			–6, –5, –4

All specifications are subject to change without notice.

IOB Input Switching Characteristics Standard Adjustments

Description	Symbol	Standard(1)	Speed Grade				Units
			Min	-6	-5	-4	
Data Input Delay Adjustments							
Standard-specific data input delay adjustments	T_{ILVTTL}	LVTTL	0	0	0	0	ns
	$T_{ILVCMOS2}$	LVCMOS2	–0.02	–0.04	–0.04	–0.05	ns
	T_{IPCI33_3}	PCI, 33 MHz, 3.3 V	–0.05	–0.11	–0.12	–0.14	ns
	T_{IPCI33_5}	PCI, 33 MHz, 5.0 V	0.13	0.25	0.28	0.33	ns
	T_{IPCI66_3}	PCI, 66 MHz, 3.3 V	–0.05	–0.11	–0.12	–0.14	ns
	T_{IGTL}	GTL	0.10	0.20	0.23	0.26	ns
	T_{IGTLP}	GTL+	0.06	0.11	0.12	0.14	ns
	T_{IHSTL}	HSTL	0.02	0.03	0.03	0.04	ns
	T_{ISSTL2}	SSTL2	–0.04	–0.08	–0.09	–0.10	ns
	T_{ISSTL3}	SSTL3	–0.02	–0.04	–0.05	–0.06	ns
	T_{ICTT}	CTT	0.01	0.02	0.02	0.02	ns
	T_{IAGP}	AGP	–0.03	–0.06	–0.07	–0.08	ns

Notes:
1. Input timing for LVTTL is measured at 1.4 V. For other I/O standards, see Table 3.

IOB Output Switching Characteristics

Output delays terminating at a pad are specified for LVTTL with 12 mA drive and fast slew rate. For other standards, adjust the delays with the values shown in **IOB Output Switching Characteristics Standard Adjustments**, page 9.

Description	Symbol	Speed Grade				Units
		Min	-6	-5	-4	
Propagation Delays						
O input to Pad	T_{IOOP}	1.2	2.9	3.2	3.5	ns, max
O input to Pad via transparent latch	T_{IOOLP}	1.4	3.4	3.7	4.0	ns, max
3-State Delays						
T input to Pad high-impedance(1)	T_{IOTHZ}	1.0	2.0	2.2	2.4	ns, max
T input to valid data on Pad	T_{IOTON}	1.4	3.1	3.3	3.7	ns, max
T input to Pad high-impedance via transparent latch(1)	$T_{IOTLPHZ}$	1.2	2.4	2.6	3.0	ns, max
T input to valid data on Pad via transparent latch	$T_{IOTLPON}$	1.6	3.5	3.8	4.2	ns, max
GTS to Pad high impedance(1)	T_{GTS}	2.5	4.9	5.5	6.3	ns, max
Sequential Delays						
Clock CLK						
Minimum Pulse Width, High	T_{CH}	0.8	1.5	1.7	2.0	ns, min
Minimum Pulse Width, Low	T_{CL}	0.8	1.5	1.7	2.0	ns, min

Calculation of T_{ioop} as a Function of Capacitance

T_{ioop} is the propagation delay from the O Input of the IOB to the pad. The values for T_{ioop} were based on the standard capacitive load (Csl) for each I/O standard as listed in Table 2.

Table 2: **Constants for Calculating T_{ioop}**

Standard	Csl (pF)	fl (ns/pF)
LVTTL Fast Slew Rate, 2mA drive	35	0.41
LVTTL Fast Slew Rate, 4mA drive	35	0.20
LVTTL Fast Slew Rate, 6mA drive	35	0.13
LVTTL Fast Slew Rate, 8mA drive	35	0.079
LVTTL Fast Slew Rate, 12mA drive	35	0.044
LVTTL Fast Slew Rate, 16mA drive	35	0.043
LVTTL Fast Slew Rate, 24mA drive	35	0.033
LVTTL Slow Slew Rate, 2mA drive	35	0.41
LVTTL Slow Slew Rate, 4mA drive	35	0.20
LVTTL Slow Slew Rate, 6mA drive	35	0.100
LVTTL Slow Slew Rate, 8mA drive	35	0.086
LVTTL Slow Slew Rate, 12mA drive	35	0.058
LVTTL Slow Slew Rate, 16mA drive	35	0.050
LVTTL Slow Slew Rate, 24mA drive	35	0.048
LVCMOS2	35	0.041
PCI 33MHz 5V	50	0.050
PCI 33MHZ 3.3 V	10	0.050
PCI 66 MHz 3.3 V	10	0.033
GTL	0	0.014
GTL+	0	0.017
HSTL Class I	20	0.022
HSTL Class III	20	0.016
HSTL Class IV	20	0.014
SSTL2 Class I	30	0.028
SSTL2 Class II	30	0.016
SSTL3 Class I	30	0.029
SSTL3 Class II	30	0.016
CTT	20	0.035
AGP	10	0.037

Notes:
1. I/O parameter measurements are made with the capacitance values shown above. See Application Note XAPP133 on www.xilinx.com for appropriate terminations.
2. I/O standard measurements are reflected in the IBIS model information except where the IBIS format precludes it.

For other capacitive loads, use the formulas below to calculate the corresponding T_{ioop}.

$$T_{ioop} = T_{ioop} + T_{opadjust} + (C_{load} - C_{sl}) * fl$$

Where:

$T_{opadjust}$ is reported above in the Output Delay Adjustment section.

C_{load} is the capacitive load for the design.

Table 3: **Delay Measurement Methodology**

Standard	V_L (1)	V_H (1)	Meas. Point	V_{REF} Typ (2)
LVTTL	0	3	1.4	-
LVCMOS2	0	2.5	1.125	-
PCI33_5	Per PCI Spec			-
PCI33_3	Per PCI Spec			-
PCI66_3	Per PCI Spec			-
GTL	V_{REF} –0.2	V_{REF} +0.2	V_{REF}	0.80
GTL+	V_{REF} –0.2	V_{REF} +0.2	V_{REF}	1.0
HSTL Class I	V_{REF} –0.5	V_{REF} +0.5	V_{REF}	0.75
HSTL Class III	V_{REF} –0.5	V_{REF} +0.5	V_{REF}	0.90
HSTL Class IV	V_{REF} –0.5	V_{REF} +0.5	V_{REF}	0.90
SSTL3 I & II	V_{REF} –1.0	V_{REF} +1.0	V_{REF}	1.5
SSTL2 I & II	V_{REF} –0.75	V_{REF} +0.75	V_{REF}	1.25
CTT	V_{REF} –0.2	V_{REF} +0.2	V_{REF}	1.5
AGP	V_{REF} – (0.2xV_{CCO})	V_{REF} + (0.2xV_{CCO})	V_{REF}	Per AGP Spec

Notes:
1. Input waveform switches between V_L and V_H.
2. Measurements are made at VREF (Typ), Maximum, and Minimum. Worst-case values are reported.
3. I/O parameter measurements are made with the capacitance values shown in Table 2. See Application Note XAPP133 on www.xilinx.com for appropriate terminations.
4. I/O standard measurements are reflected in the IBIS model information except where the IBIS format precludes it.

Clock Distribution Guidelines

Description	Device	Symbol	Speed Grade			Units
			-6	-5	-4	
Global Clock Skew(1)						
Global Clock Skew between IOB Flip-flops	XCV50	$T_{GSKEWIOB}$	0.10	0.12	0.14	ns, max
	XCV100		0.12	0.13	0.15	ns, max
	XCV150		0.12	0.13	0.15	ns, max
	XCV200		0.13	0.14	0.16	ns, max
	XCV300		0.14	0.16	0.18	ns, max
	XCV400		0.13	0.13	0.14	ns, max
	XCV600		0.14	0.15	0.17	ns, max
	XCV800		0.16	0.17	0.20	ns, max
	XCV1000		0.20	0.23	0.25	ns, max

Notes:
1. These clock-skew delays are provided for guidance only. They reflect the delays encountered in a typical design under worst-case conditions. Precise values for a particular design are provided by the timing analyzer.

Clock Distribution Switching Characteristics

Description	Symbol	Speed Grade				Units
		Min	-6	-5	-4	
GCLK IOB and Buffer						
Global Clock PAD to output.	T_{GPIO}	0.33	0.7	0.8	0.9	ns, max
Global Clock Buffer I input to O output	T_{GIO}	0.34	0.7	0.8	0.9	ns, max

CLB Switching Characteristics

Delays originating at F/G inputs vary slightly according to the input used. The values listed below are worst-case. Precise values are provided by the timing analyzer.

Description	Symbol	Speed Grade				Units
		Min	-6	-5	-4	
Combinatorial Delays						
4-input function: F/G inputs to X/Y outputs	T_{ILO}	0.29	0.6	0.7	0.8	ns, max
5-input function: F/G inputs to F5 output	T_{IF5}	0.32	0.7	0.8	0.9	ns, max
5-input function: F/G inputs to X output	T_{IF5X}	0.36	0.8	0.8	1.0	ns, max
6-input function: F/G inputs to Y output via F6 MUX	T_{IF6Y}	0.44	0.9	1.0	1.2	ns, max
6-input function: F5IN input to Y output	T_{F5INY}	0.17	0.32	0.36	0.42	ns, max
Incremental delay routing through transparent latch to XQ/YQ outputs	T_{IFNCTL}	0.31	0.7	0.7	0.8	ns, max
BY input to YB output	T_{BYYB}	0.27	0.53	0.6	0.7	ns, max
Sequential Delays						
FF Clock CLK to XQ/YQ outputs	T_{CKO}	0.54	1.1	1.2	1.4	ns, max
Latch Clock CLK to XQ/YQ outputs	T_{CKLO}	0.6	1.2	1.4	1.6	ns, max
Setup and Hold Times before/after Clock CLK(1)	Setup Time / Hold Time					
4-input function: F/G Inputs	T_{ICK}/T_{CKI}	0.6 / 0	1.2 / 0	1.4 / 0	1.5 / 0	ns, min
5-input function: F/G inputs	T_{IF5CK}/T_{CKIF5}	0.7 / 0	1.3 / 0	1.5 / 0	1.7 / 0	ns, min
6-input function: F5IN input	T_{F5INCK}/T_{CKF5IN}	0.46 / 0	1.0 / 0	1.1 / 0	1.2 / 0	ns, min
6-input function: F/G inputs via F6 MUX	T_{IF6CK}/T_{CKIF6}	0.8 / 0	1.5 / 0	1.7 / 0	1.9 / 0	ns, min
BX/BY inputs	T_{DICK}/T_{CKDI}	0.30 / 0	0.6 / 0	0.7 / 0	0.8 / 0	ns, min
CE input	T_{CECK}/T_{CKCE}	0.37 / 0	0.8 / 0	0.9 / 0	1.0 / 0	ns, min
SR/BY inputs (synchronous)	$T_{RCK}T_{CKR}$	0.33 / 0	0.7 / 0	0.8 / 0	0.9 / 0	ns, min
Clock CLK						
Minimum Pulse Width, High	T_{CH}	0.8	1.5	1.7	2.0	ns, min
Minimum Pulse Width, Low	T_{CL}	0.8	1.5	1.7	2.0	ns, min
Set/Reset						
Minimum Pulse Width, SR/BY inputs	T_{RPW}	1.3	2.5	2.8	3.3	ns, min
Delay from SR/BY inputs to XQ/YQ outputs (asynchronous)	T_{RQ}	0.54	1.1	1.3	1.4	ns, max
Delay from GSR to XQ/YQ outputs	T_{IOGSRQ}	4.9	9.7	10.9	12.5	ns, max
Toggle Frequency (MHz) (for export control)	F_{TOG} (MHz)	625	333	294	250	MHz

Notes:
1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values cannot be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.

Virtex Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. Listed below are representative values for typical pin locations and normal clock loading. Values are expressed in nanoseconds unless otherwise noted.

Global Clock Input to Output Delay for LVTTL, 12 mA, Fast Slew Rate, *with* DLL

Description	Symbol	Device	Speed Grade				Units
			Min	-6	-5	-4	
LVTTL Global Clock Input to Output Delay using Output Flip-flop, 12 mA, Fast Slew Rate, *with* DLL. For data *output* with different standards, adjust delays with the values shown in Output Delay Adjustments.	$T_{ICKOFDLL}$	XCV50	1.0	3.1	3.3	3.6	ns, max
		XCV100	1.0	3.1	3.3	3.6	ns, max
		XCV150	1.0	3.1	3.3	3.6	ns, max
		XCV200	1.0	3.1	3.3	3.6	ns, max
		XCV300	1.0	3.1	3.3	3.6	ns, max
		XCV400	1.0	3.1	3.3	3.6	ns, max
		XCV600	1.0	3.1	3.3	3.6	ns, max
		XCV800	1.0	3.1	3.3	3.6	ns, max
		XCV1000	1.0	3.1	3.3	3.6	ns, max

Notes:
1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at 1.4 V with 35 pF external capacitive load for LVTTL. The 35 pF load does not apply to the Min values. For other I/O standards and different loads, see Table 2 and Table 3.
3. DLL output jitter is already included in the timing calculation.

Global Clock Input-to-Output Delay for LVTTL, 12 mA, Fast Slew Rate, *without* DLL

Description	Symbol	Device	Speed Grade				Units
			Min	-6	-5	-4	
LVTTL Global Clock Input to Output Delay using Output Flip-flop, 12 mA, Fast Slew Rate, *without* DLL. For data *output* with different standards, adjust delays with the values shown in Input and Output Delay Adjustments. For I/O standards requiring V_{REF}, such as GTL, GTL+, SSTL, HSTL, CTT, and AGO, an additional 600 ps must be added.	T_{ICKOF}	XCV50	1.5	4.6	5.1	5.7	ns, max
		XCV100	1.5	4.6	5.1	5.7	ns, max
		XCV150	1.5	4.7	5.2	5.8	ns, max
		XCV200	1.5	4.7	5.2	5.8	ns, max
		XCV300	1.5	4.7	5.2	5.9	ns, max
		XCV400	1.5	4.8	5.3	6.0	ns, max
		XCV600	1.6	4.9	5.4	6.0	ns, max
		XCV800	1.6	4.9	5.5	6.2	ns, max
		XCV1000	1.7	5.0	5.6	6.3	ns, max

Notes:
1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at 1.4 V with 35 pF external capacitive load for LVTTL. The 35 pF load does not apply to the Min values. For other I/O standards and different loads, see Table 2 and Table 3.

Table 3: **Virtex Pinout Tables (BGA) *(Continued)***

Pin Name	Device	BG256	BG352	BG432	BG560
V_{REF}, Bank 3 (V_{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V_{REF} pins are general I/O.	XCV50	M18, V20	N/A	N/A	N/A
	XCV100/150	... + R19	R4, V4, Y3	N/A	N/A
	XCV200/300	... + P18	... + AC2	V2, AB4, AD4, AF3	N/A
	XCV400	N/A	N/A	... + U2	V4, W5, AD3, AE5, AK2
	XCV600	N/A	N/A	... + AC3	... + AF1
	XCV800	N/A	N/A	... + Y3	... + AA4
	XCV1000	N/A	N/A	N/A	... + AH4
V_{REF}, Bank 4 (V_{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V_{REF} pins are general I/O.	XCV50	V12, Y18	N/A	N/A	N/A
	XCV100/150	... + W15	AC12, AE5, AE8,	N/A	N/A
	XCV200/300	... + V14	... + AE4	AJ7, AL4, AL8, AL13	N/A
	XCV400	N/A	N/A	... + AK15	AL7, AL10, AL16, AM4, AM14
	XCV600	N/A	N/A	... + AK8	... + AL9
	XCV800	N/A	N/A	... + AJ12	... + AK13
	XCV1000	N/A	N/A	N/A	... + AN3
V_{REF}, Bank 5 (V_{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V_{REF} pins are general I/O.	XCV50	V9, Y3	N/A	N/A	N/A
	XCV100/150	... + W6	AC15, AC18, AD20	N/A	N/A
	XCV200/300	... + V7	... + AE23	AJ18, AJ25, AK23, AK27	N/A
	XCV400	N/A	N/A	... + AJ17	AJ18, AJ25, AL20, AL24, AL29
	XCV600	N/A	N/A	... + AL24	... + AM26
	XCV800	N/A	N/A	... + AH19	... + AN23
	XCV1000	N/A	N/A	N/A	... + AK28
V_{REF}, Bank 6 (V_{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V_{REF} pins are general I/O.	XCV50	M2, R3	N/A	N/A	N/A
	XCV100/150	... + T1	R24, Y26, AA25,	N/A	N/A
	XCV200/300	... + T3	... + AD26	V28, AB28, AE30, AF28	N/A
	XCV400	N/A	N/A	... + U28	V29, Y32, AD31, AE29, AK32
	XCV600	N/A	N/A	... + AC28	... + AE31
	XCV800	N/A	N/A	... + Y30	... + AA30
	XCV1000	N/A	N/A	N/A	... + AH30

Table 4: **Virtex Pinout Tables (Fine-Pitch BGA) *(Continued)***

Pin Name	Device	FG256	FG456	FG676	FG680
V_{REF}, Bank 7 (V_{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V_{REF} pins are general I/O.	XCV50	C1, H3	N/A	N/A	N/A
	XCV100/150	... + D1	E2, H4, K3	N/A	N/A
	XCV200/300	... + B1	... + D2	N/A	N/A
	XCV400	N/A	N/A	F4, G4, K6, M2, M5	N/A
	XCV600	N/A	N/A	... + H1	E38, G38, L36, N36, U36, U38
	XCV800	N/A	N/A	... + K1	... + N38
	XCV1000	N/A	N/A	N/A	... + F36
GND	All	A1, A16, B2, B15, F6, F7, F10, F11, G6, G7, G8, G9, G10, G11, H7, H8, H9, H10, J7, J8, J9, J10, K6, K7, K8, K9, K10, K11, L6, L7, L10, L11, R2, R15, T1, T16	A1, A22, B2, B21, C3, C20, J9, J10, J11, J12, J13, J14, K9, K10, K11, K12, K13, K14, L9, L10, L11, L12, L13, L14, M9, M10, M11, M12, M13, M14, N9, N10, N11, N12, N13, N14, P9, P10, P11, P12, P13, P14, Y3, Y20, AA2, AA21, AB1, AB22	A1, A26, B2, B9, B14, B18, B25, C3, C24, D4, D23, E5, E22, J2, J25, K10, K11, K12, K13, K14, K15, K16, K17, L10, L11, L12, L13, L14, L15, L16, L17, M10, M11, M12, M13, M14, M15, M16, M17, N2, N10, N11, N12, N13, N14, N15, N16, N17, P10, P11, P12, P13, P14, P15, P16, P17, P25, R10, R11, R12, R13, R14, R15, R16, R17, T10, T11, T12, T13, T14, T15, T16, T17, U10, U11, U12, U13, U14, U15, U16, U17, V2, V25, AB5, AB22, AC4, AC23, AD3, AD24, AE2, AE9, AE13, AE18, AE25, AF1, AF26	A1, A2, A3, A37, A38, A39, AA5, AA35, AH4, AH5, AH35, AH36, AR5, AR12, AR19, AR20, AR21, AR28, AR35, AT4, AT12, AT20, AT28, AT36, AU1, AU3, AU20, AU37, AU39, AV1, AV2, AV38, AV39, AW1, AW2, AW3, AW37, AW38, AW39, B1, B2, B38, B39, C1, C3, C20, C37, C39, D4, D12, D20, D28, D36, E5, E12, E19, E20, E21, E28, E35, M4, M5, M35, M36, W5, W35, Y3, Y4, Y5, Y35, Y36, Y37

BG256 Pin Function Diagram

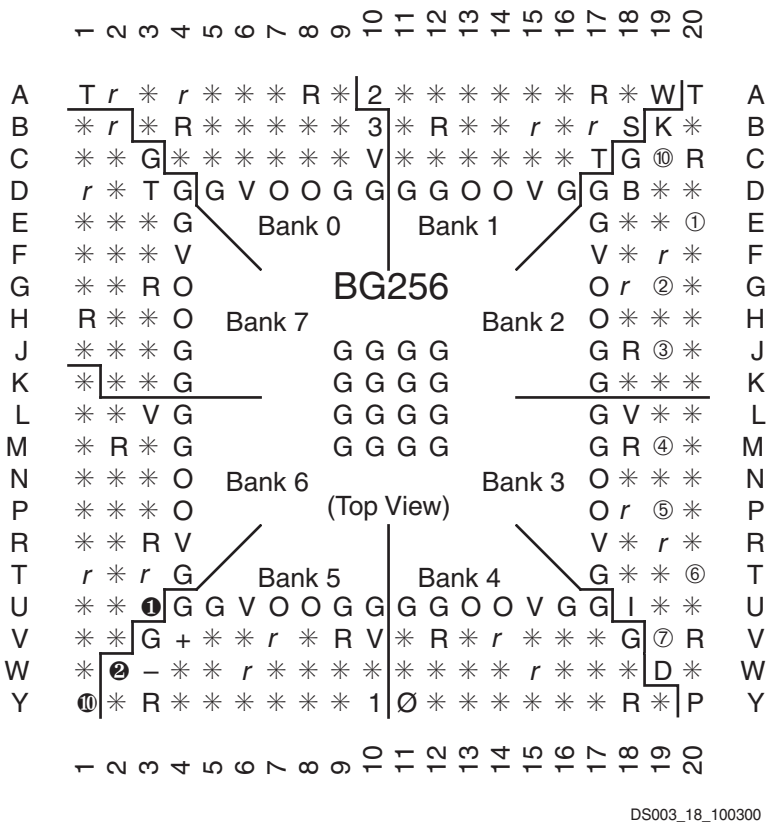


Figure 4: **BG256 Pin Function Diagram**

BG352 Pin Function Diagram

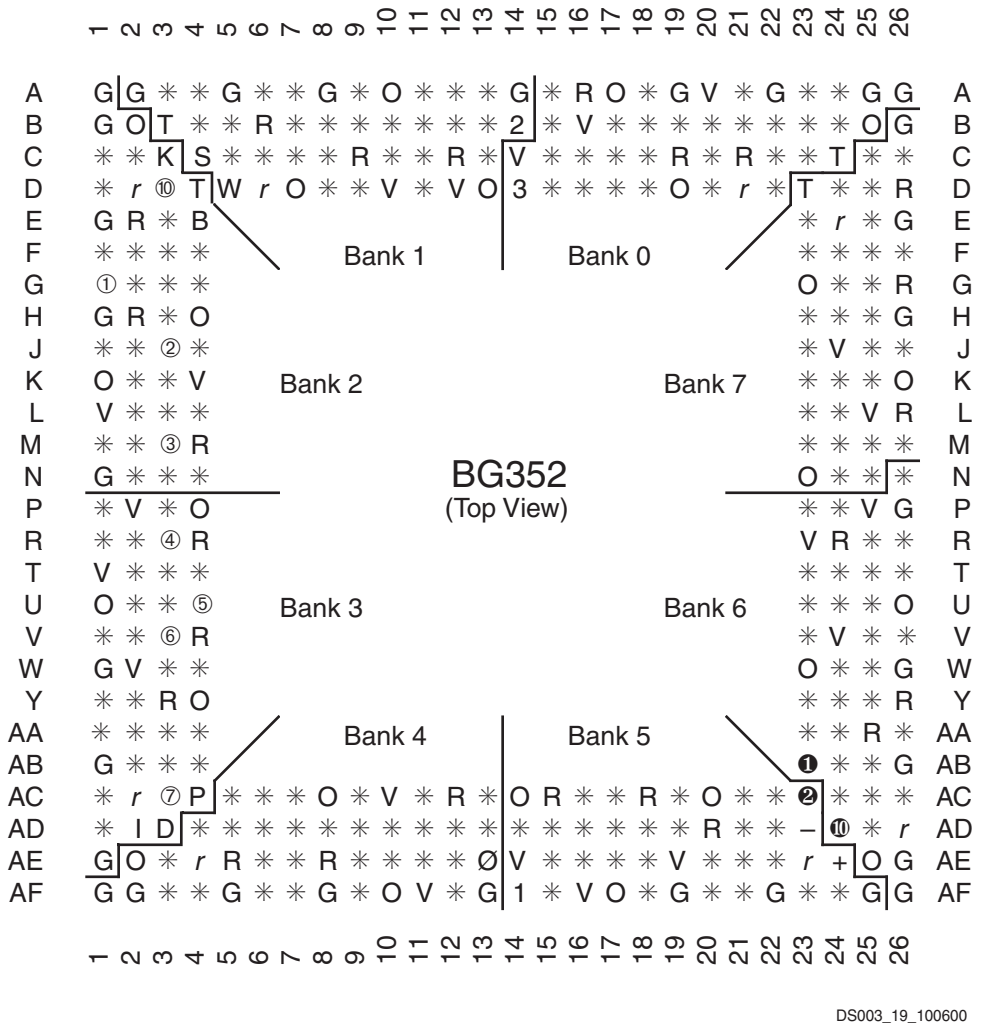


Figure 5: **BG352 Pin Function Diagram**

BG432 Pin Function Diagram

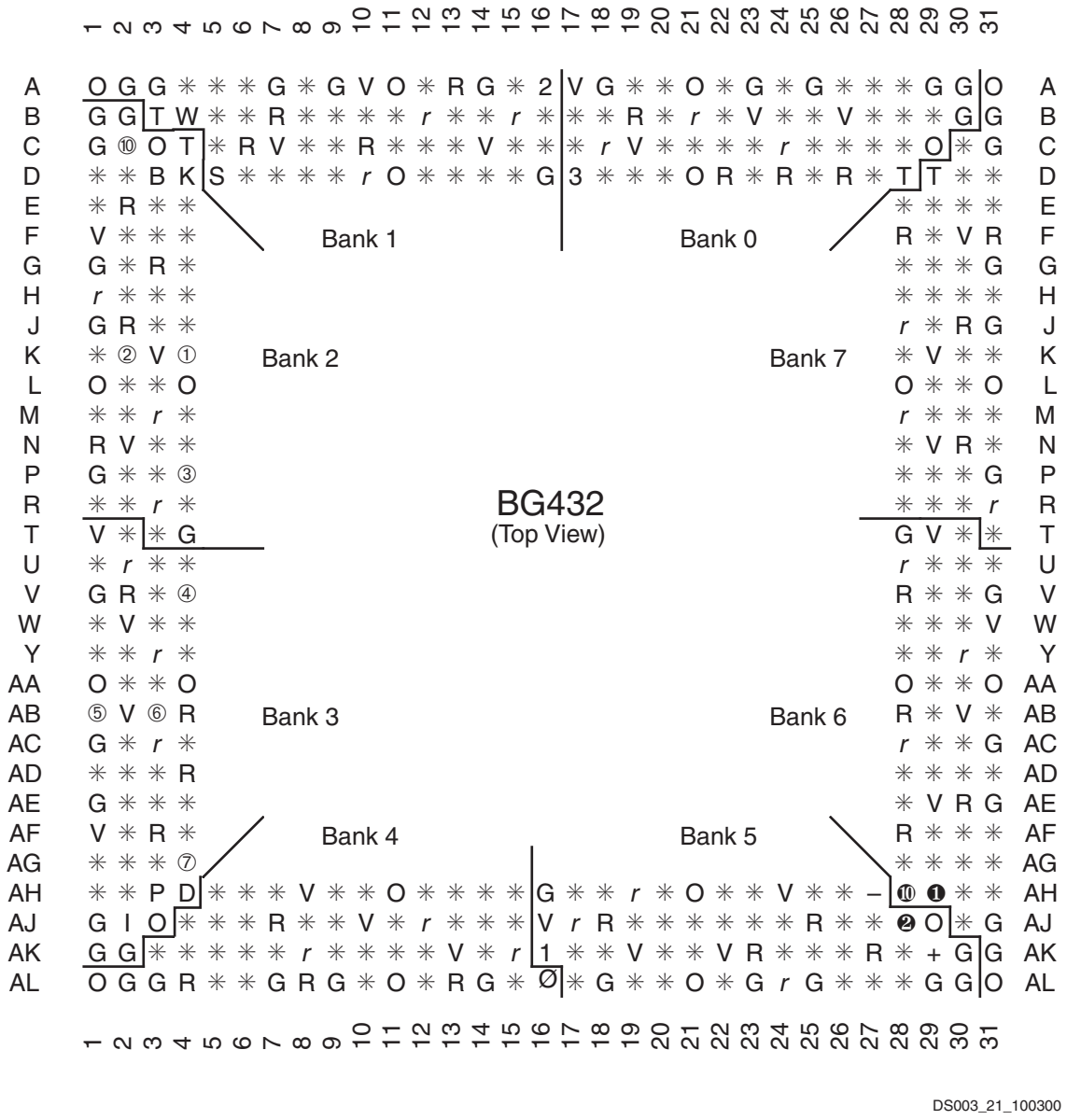
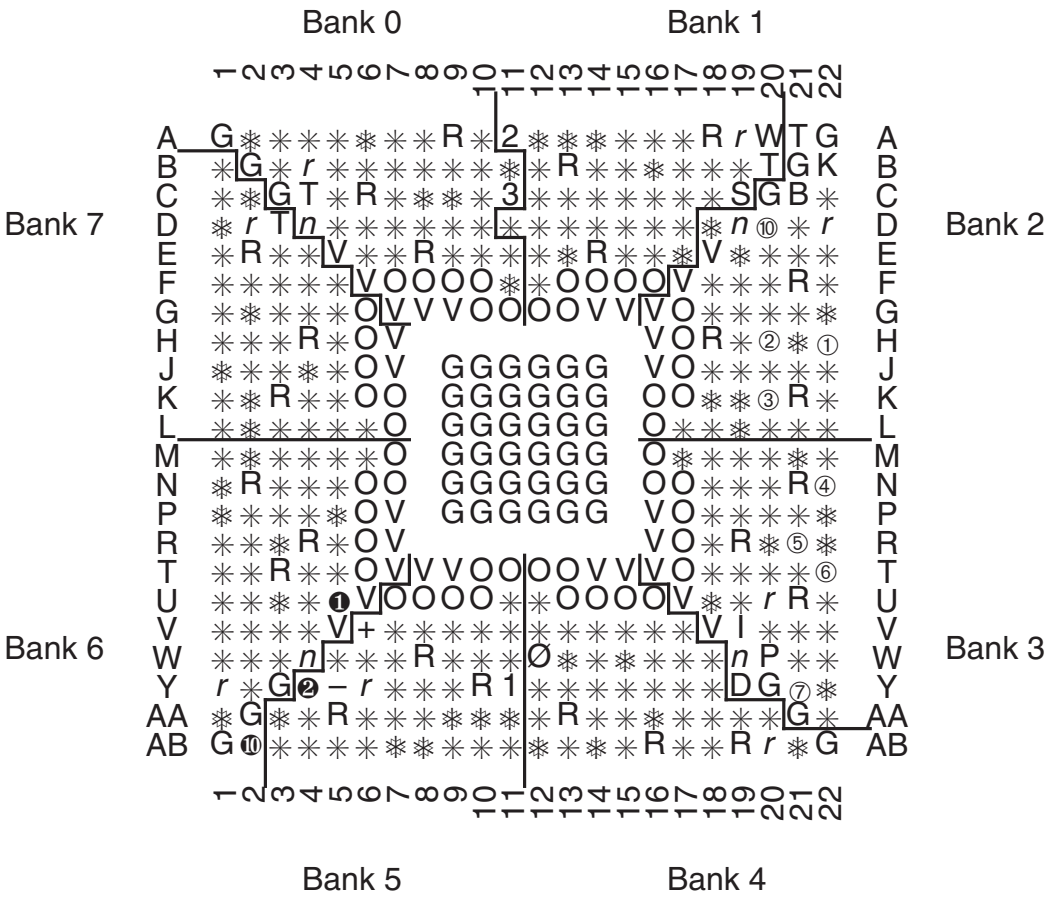


Figure 6: **BG432 Pin Function Diagram**

FG456 Pin Function Diagram



FG456
(Top view)

Figure 9: **FG456 Pin Function Diagram**

Notes:

Packages FG456 and FG676 are layout compatible.

FG676 Pin Function Diagram

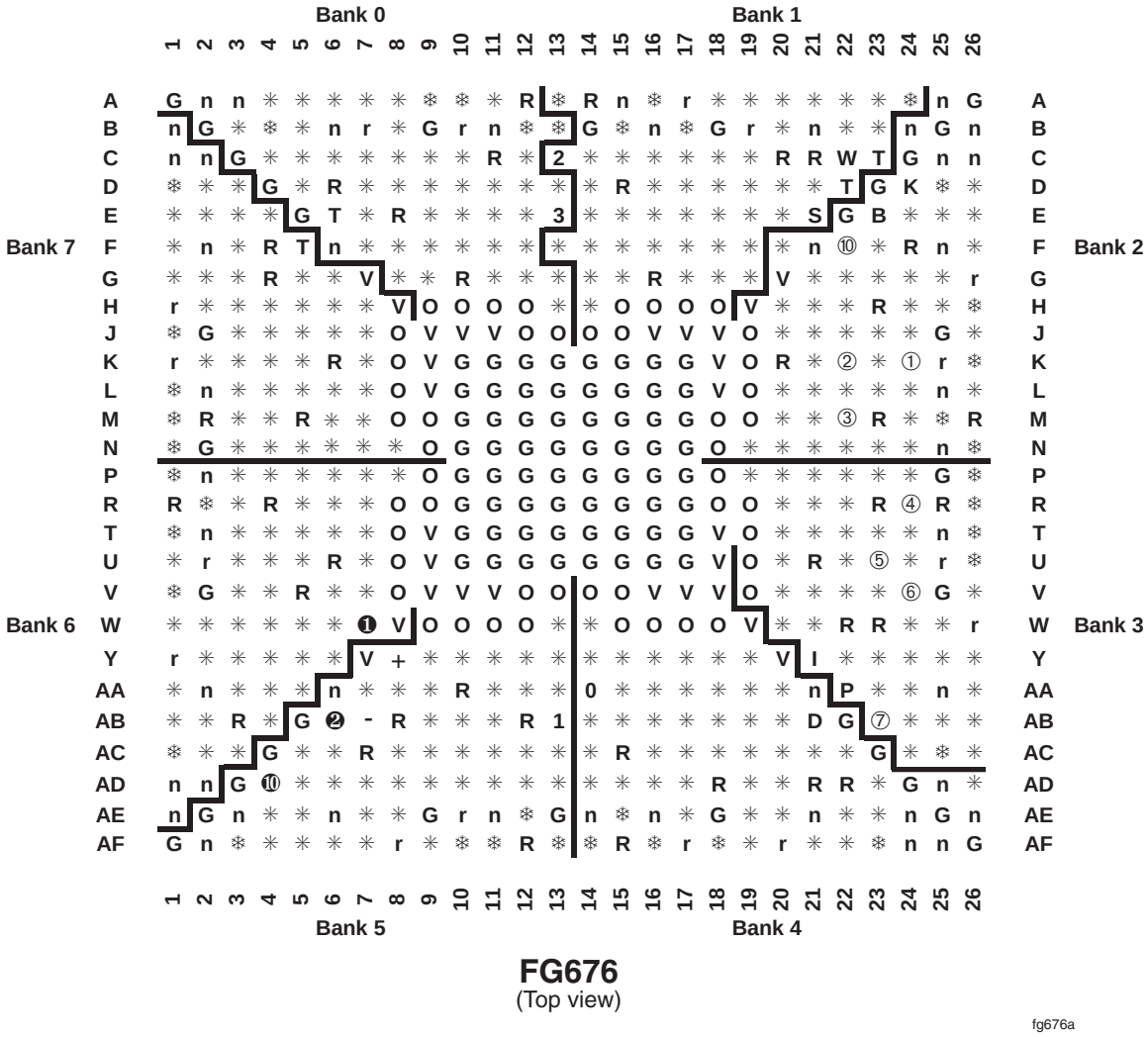


Figure 10: **FG676 Pin Function Diagram**

Notes:

Packages FG456 and FG676 are layout compatible.

FG680 Pin Function Diagram

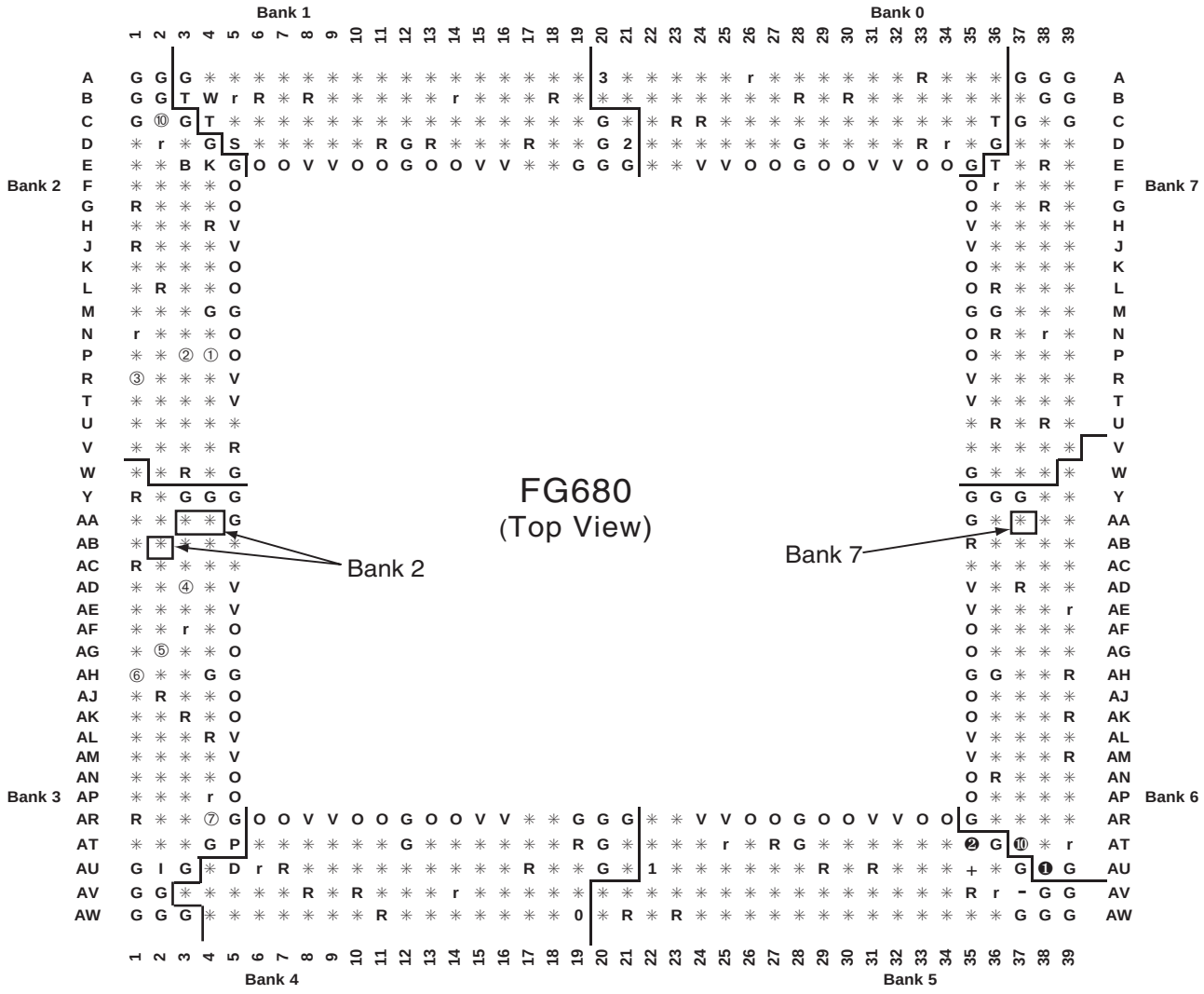


Figure 11: **FG680 Pin Function Diagram**